XPP: X-ray Pump Probe station at BESSY II

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Abstract: The X-ray Pump-Probe (XPP) experimental station predominantly aims at investigating hard and soft matter under a broad range of ambient conditions using time-resolved X-ray diffraction.

1 Introduction

The X-ray Pump-Probe (XPP) experimental station is dedicated to time-resolved material research of solid-state and soft condensed matter systems. The station utilizes a fiber-based femtosecond laser systems that yields optical pulses of 250 fs duration and 10 µJ pulse energy at variable repetition rates of up to 1.25 MHz. The sample environment comprises an in-vacuum 4-circle diffractometer with cryostat for cooling down to 20 K. Diffracted X-ray photons are detected with a hybrid pixel area detector allowing for ultrafast reciprocal space mapping.

Optical pump light and the X-ray probe pulses enter the vacuum chamber on quasi collinear beam paths. The goniometer axes allow for scanning of a large reciprocal space volume while preserving the illuminated pump area on the sample surface. Hence, several in-plane and out-of-plane diffraction peaks can be measured under comparable optical pump conditions.

The setup is specifically optimized for experiments at high laser repetition rates where fast heat removal from the excited samples is required. Two cooling options are provided:

1. The sample holder is connected to a 4 K cryostat via flexible copper wires. While allowing full mechanical flexibility the sample can be cooled down to temperatures of less than 20 K without laser excitation. Exciting the sample with the high repetition laser system leads to a typical static temperature increase of up to 100 K depending on laser power and sample heat conduction.

2. At ambient pressure the excited sample surface can be directly cooled with a cold nitrogen jet. The temperature range of the coolant extends from room temperature to 90 K. This configuration can either be used for efficient heat removal from the excited sample surface or for real cooling to cryogenic temperatures.

Samples are excited by ultrafast optical pulses emitted from an ytterbium-doped fiber laser. Laser parameters are listed in Table 1. Alternative excitation concepts are currently developed, e.g., sample excitation with ultrashort current or voltage pulses. The XPP-station is fully operational since April 2015.

## 2 Instrument application

- Thermal transport in nanoscale systems
- Coherent lattice dynamics
- Electronic and magnetic coupling to the crystal structure in multiferroic systems
- Phase transitions and phase change materials
- New methods for time-resolved XRD

## 3 Technical data

The laser source is a multi-stage ytterbium-doped oscillator - amplifier system (Impulse, Clark-MXR). It is synchronized to the RF-signal of the storage ring with accuracy better than 5 ps. The main laser parameters are:

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Specification</th>
</tr>
</thead>
<tbody>
<tr>
<td>Repetition Rate</td>
<td>Adjustable by user from 200 kHz to 25 MHz</td>
</tr>
<tr>
<td>Pulse Energy</td>
<td>Adjustable by user:</td>
</tr>
<tr>
<td></td>
<td>0.8 µJ @ ( f_{\text{rep}} &gt; 2 \text{ MHz} &lt; 25 \text{ MHz} )</td>
</tr>
<tr>
<td></td>
<td>10 µJ @ ( f_{\text{rep}} &lt; 2 \text{ MHz} )</td>
</tr>
<tr>
<td>Average Output Power</td>
<td>Adjustable by user: max. 10 W ( f_{\text{rep}} = 2 \text{ MHz} ) typical operation: 2 W ( f_{\text{rep}} = 208 \text{ kHz} )</td>
</tr>
<tr>
<td>Pulse Duration</td>
<td>250 fs</td>
</tr>
<tr>
<td>Center Wavelength</td>
<td>1030 nm</td>
</tr>
<tr>
<td>Pump probe delay</td>
<td>up to 5 µs ( f_{\text{rep}} = 208 \text{ kHz} ) with 4 ps resolution</td>
</tr>
</tbody>
</table>

Table 1: Specification of the excitation laser.

Specifications of the Beamline and of the sample environment are listed in Table 2. The diffractometer in the vacuum vessel is shown in Figure 1.
Table 2: Specification of the sample environment.

<table>
<thead>
<tr>
<th>Monochromator</th>
<th>U41-FSGM</th>
</tr>
</thead>
<tbody>
<tr>
<td>Experiment in vacuum</td>
<td>Yes</td>
</tr>
<tr>
<td>Temperature range</td>
<td>&lt;20 K to room temperature</td>
</tr>
</tbody>
</table>

Detector
- Dectris, Pilatus 100k hybrid pixel area detector
- Home-build fast scintillator (trise < 1 ns) + time-correlated SPC
- CyberStar Scintillator Detector
- Energy dispersive detector: (XFlash, Roentec; ΔE/E ≈ 170 eV @8 keV)

Manipulators
Diffractometer layout:
3 sample circles:

<table>
<thead>
<tr>
<th>Circle</th>
<th>With Cryostat</th>
<th>Without Cryostat</th>
</tr>
</thead>
<tbody>
<tr>
<td>ω</td>
<td>-3° - 33°</td>
<td>0° - 90°</td>
</tr>
<tr>
<td>φ</td>
<td>-10° - 100°</td>
<td>0° - 360°</td>
</tr>
<tr>
<td>χ</td>
<td>0° - 180°</td>
<td>0° - 180°</td>
</tr>
</tbody>
</table>

1 detector circle (Θ): 0° - 110°
x-y-z- translation for sample positioning
adjustment of optical pump - X-ray probe overlap via transversal positioning of focusing lens

Figure 1: Diffractometer in the vacuum vessel.
References


